

ESREF Best Paper Reference

Each year IRPS invites the winner of the ESREF Best Paper Award to present that paper at IRPS. The reference for this year's paper is:

On the Temperature Dependence of NBTI Recovery,
*Thomas Aichinger, KAI (Kompetenzzentrum Automobil und
Industrie-Elektronik), Michael Nelhiesel, Infineon
Technologies Austria, Tibor Grasser, TU Wien,
Microelectronics Reliability, vol 48, pp. 1178-1184 (2008).*